

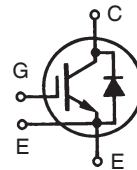
IGBT with Diode

Short Circuit SOA Capability

IXSN 80N60BD1

$V_{CES} = 600 \text{ V}$
 $I_{C25} = 160 \text{ A}$
 $V_{CE(sat)} = 2.5 \text{ V}$
 $t_{fi} = 180 \text{ ns}$

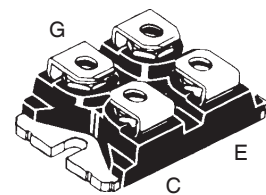
Preliminary Data Sheet



| Symbol | Test Conditions | Maximum Ratings |
|------------------------------------|--|--|
| V_{CES} | $T_J = 25^\circ\text{C}$ to 150°C | 600 V |
| V_{CGR} | $T_J = 25^\circ\text{C}$ to 150°C ; $R_{GE} = 1 \text{ M}\Omega$ | 600 A |
| V_{GES} | Continuous | ± 20 V |
| V_{GEM} | Transient | ± 30 V |
| I_{C25} | $T_C = 25^\circ\text{C}$ (Silicon chip capability) | 160 A |
| I_L | Lead current limit (RMS) | 100 A |
| I_{C90} | $T_C = 90^\circ\text{C}$ | 80 A |
| I_{CM} | $T_C = 25^\circ\text{C}$, 1 ms | 300 A |
| SSOA (RBSOA) | $V_{GE} = 15 \text{ V}$, $T_{VJ} = 125^\circ\text{C}$, $R_G = 5 \Omega$ Clamped inductive load | $I_{CM} = 160$ @ $0.8 V_{CES}$ |
| t_{SC} (SCSOA) | $V_{GE} = 15 \text{ V}$, $V_{CE} = 360 \text{ V}$, $T_J = 125^\circ\text{C}$ $R_G = 22 \Omega$, non repetitive | 10 μs |
| P_C | $T_C = 25^\circ\text{C}$ | 420 W |
| V_{ISOL} | 50/60 Hz $I_{ISOL} \leq 1 \text{ mA}$ | t = 1 min: 2500 V~ t = 1 s: 3000 V~ |
| T_J | | -55 ... +150 $^\circ\text{C}$ |
| T_{JM} | | 150 $^\circ\text{C}$ |
| T_{stg} | | -55 ... +150 $^\circ\text{C}$ |
| M_d | Mounting torque | 0.4/6 Nm/lb.in. |
| Weight | | 30 g |

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E153432 E



E = Emitter ①, C = Collector
G = Gate, E = Emitter ②

① Either Emitter terminal can be used as Main or Kelvin Emitter

Features

- International standard package
- Aluminium-nitride isolation
 - high power dissipation
- Isolation voltage 3000 V~
- UL registered E 153432
- Low $V_{CE(sat)}$
 - for minimum on-state conduction losses
- Fast Recovery Epitaxial Diode
 - short t_{tr} and I_{RM}
- Low collector-to-case capacitance (< 60 pF)
 - reduced RFI
- Low package inductance (< 10 nH)
 - easy to drive and to protect

Applications

- AC motor speed control
- DC servo and robot drives
- DC choppers
- Uninterruptible power supplies (UPS)
- Switch-mode and resonant-mode power supplies

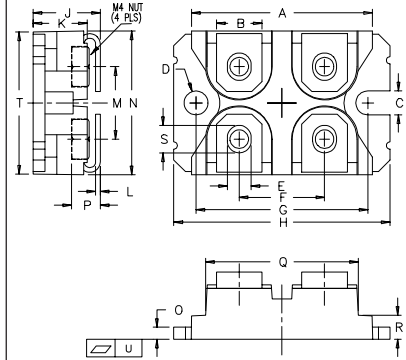
Advantages

- Space savings
- Easy to mount with 2 screws
- High power density

| Symbol | Test Conditions | Characteristic Values ($T_J = 25^\circ\text{C}$, unless otherwise specified) | | |
|---------------|--|---|------|--|
| | | min. | typ. | max. |
| BV_{CES} | $I_C = 500 \mu\text{A}$, $V_{GE} = 0 \text{ V}$ | 600 | | V |
| $V_{GE(th)}$ | $I_C = 8 \text{ mA}$, $V_{CE} = V_{GE}$ | 4 | | V |
| I_{CES} | $V_{CE} = V_{CES}$ $V_{GE} = 0 \text{ V}$ | | | $T_J = 25^\circ\text{C}$: 200 μA $T_J = 125^\circ\text{C}$: 2 mA |
| I_{GES} | $V_{CE} = 0 \text{ V}$, $V_{GE} = \pm 20 \text{ V}$ | | | ± 200 nA |
| $V_{CE(sat)}$ | $I_C = I_{C90}$, $V_{GE} = 15 \text{ V}$; Note 1 | | | 2.5 V |

IXYS reserves the right to change limits, test conditions and dimensions.

| Symbol | Test Conditions | Characteristic Values ($T_J = 25^\circ\text{C}$, unless otherwise specified) | | | |
|--------------|---|---|------|------|----|
| | | min. | typ. | max. | |
| g_{fs} | $I_C = 60\text{ A}$; $V_{CE} = 10\text{ V}$, Note1 | 52 | | S | |
| C_{ies} | $V_{CE} = 25\text{ V}$, $V_{GE} = 0\text{ V}$, $f = 1\text{ MHz}$ | | 6600 | pF | |
| C_{oes} | | | 720 | pF | |
| C_{res} | | | 196 | pF | |
| Q_g | $I_C = I_{C90}$, $V_{GE} = 15\text{ V}$, $V_{CE} = 0.5 V_{CES}$ | | 200 | nC | |
| Q_{ge} | | | 70 | nC | |
| Q_{gc} | | | 60 | nC | |
| $t_{d(on)}$ | Inductive load, $T_J = 25^\circ\text{C}$ $I_C = I_{C90}$, $V_{GE} = 15\text{ V}$, $L = 100\ \mu\text{H}$, $V_{CE} = 0.8 V_{CES}$, $R_G = 2.7\ \Omega$ Note 2 | | 60 | ns | |
| t_{ri} | | | 50 | ns | |
| $t_{d(off)}$ | | | 140 | 280 | ns |
| t_{fi} | | | 120 | 200 | ns |
| E_{off} | | | 1.8 | 3.5 | mJ |
| $t_{d(on)}$ | Inductive load, $T_J = 125^\circ\text{C}$ $I_C = I_{C90}$, $V_{GE} = 15\text{ V}$, $L = 100\ \mu\text{H}$ $V_{CE} = 0.8 V_{CES}$, $R_G = 2.7\ \Omega$ Note 2 | | 60 | ns | |
| t_{ri} | | | 60 | ns | |
| E_{on} | | | 4.8 | mJ | |
| $t_{d(off)}$ | | | 190 | ns | |
| t_{fi} | | | 160 | ns | |
| E_{off} | | 3.3 | mJ | | |
| R_{thJC} | | | 0.30 | K/W | |
| R_{thCK} | | 0.05 | | K/W | |

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M4 screws (4x) supplied

| Dim. | Millimeter | | Inches | |
|------|------------|-------|--------|-------|
| | Min. | Max. | Min. | Max. |
| A | 31.50 | 31.88 | 1.240 | 1.255 |
| B | 7.80 | 8.20 | 0.307 | 0.323 |
| C | 4.09 | 4.29 | 0.161 | 0.169 |
| D | 4.09 | 4.29 | 0.161 | 0.169 |
| E | 4.09 | 4.29 | 0.161 | 0.169 |
| F | 14.91 | 15.11 | 0.587 | 0.595 |
| G | 30.12 | 30.30 | 1.186 | 1.193 |
| H | 38.00 | 38.23 | 1.496 | 1.505 |
| J | 11.68 | 12.22 | 0.460 | 0.481 |
| K | 8.92 | 9.60 | 0.351 | 0.378 |
| L | 0.76 | 0.84 | 0.030 | 0.033 |
| M | 12.60 | 12.85 | 0.496 | 0.506 |
| N | 25.15 | 25.42 | 0.990 | 1.001 |
| O | 1.98 | 2.13 | 0.078 | 0.084 |
| P | 4.95 | 5.97 | 0.195 | 0.235 |
| Q | 26.54 | 26.90 | 1.045 | 1.059 |
| R | 3.94 | 4.42 | 0.155 | 0.174 |
| S | 4.72 | 4.85 | 0.186 | 0.191 |
| T | 24.59 | 25.07 | 0.968 | 0.987 |
| U | -0.05 | 0.1 | -0.002 | 0.004 |

Reverse Diode (FRED)
Characteristic Values
($T_J = 25^\circ\text{C}$, unless otherwise specified)

| Symbol | Test Conditions | typ. | max. |
|------------|---|------|-----------------|
| V_F | $I_F = 60\text{ A}$, Note 1 $T_J = 150^\circ\text{C}$ | | 2.05 V 1.4 V |
| I_{RM} | $I_F = I_{C90}$, $V_{GE} = 0\text{ V}$, $-di_F/dt = 100\text{ A}/\mu\text{s}$ $V_R = 100\text{ V}$, $T_J = 100^\circ\text{C}$ | | 8.0 A |
| t_{rr} | $I_F = 1\text{ A}$, $-di/dt = 50\text{ A}/\mu\text{s}$, $V_R = 30\text{ V}$ | 35 | ns |
| R_{thJC} | | | 0.85 K/W |

 Note: 1. Pulse test, $t \leq 300\ \mu\text{s}$, duty cycle $d \leq 2\%$

Note: 2. Remarks: Switching times may increase for

 $V_{CE}(\text{Clamp}) > 0.8 \cdot V_{CES}$, higher T_J or increased R_G

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Fig. 1. Output Characteristics @ 25 Deg. C

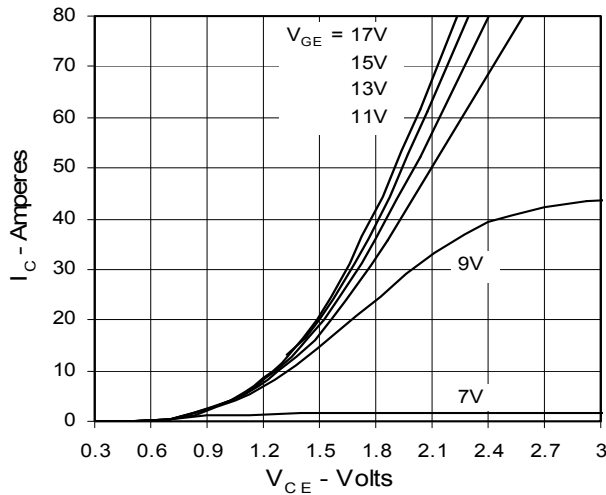


Fig. 2. Extended Output Characteristics @ 25 deg. C

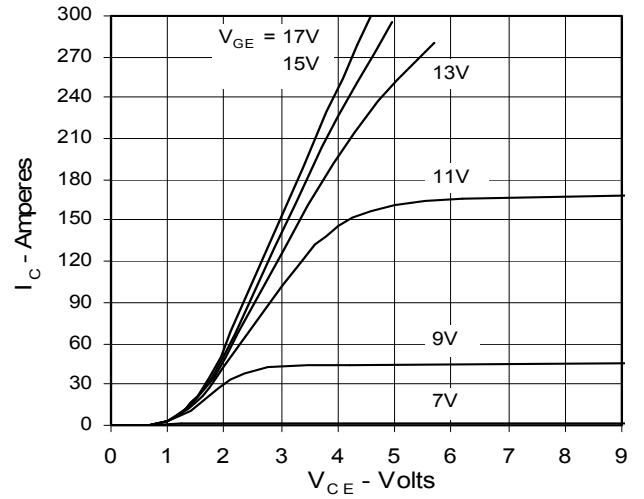


Fig. 3. Output Characteristics @ 125 Deg. C

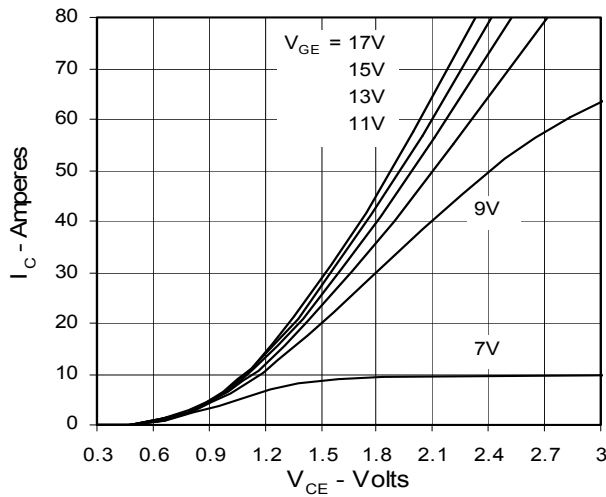


Fig. 4. Dependence of $V_{CE(sat)}$ on Temperature

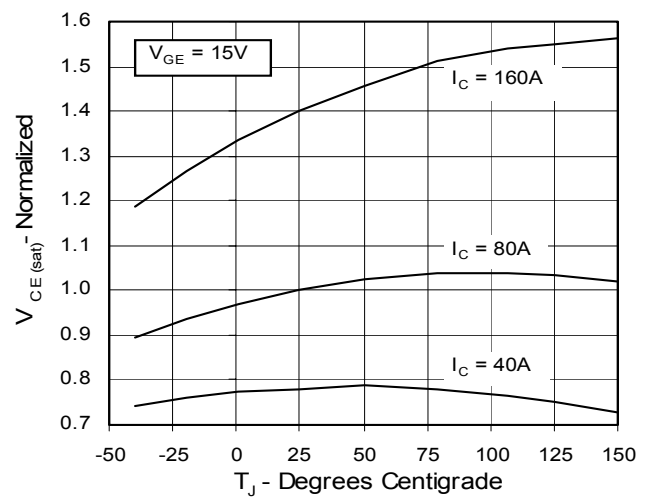


Fig. 5. Collector-to-Emitter Voltage vs. Gate-to-Emitter voltage

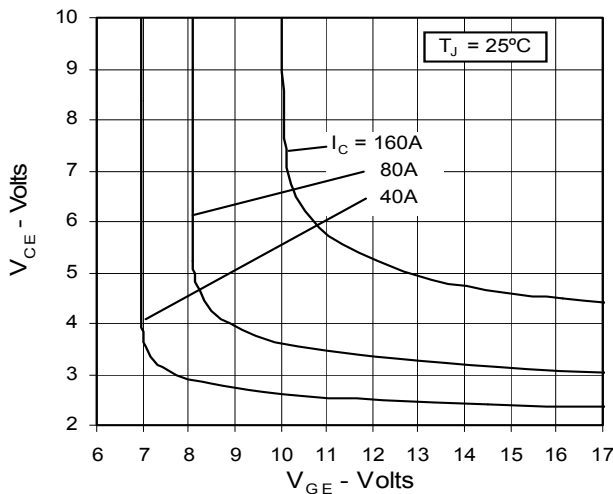


Fig. 6. Input Admittance

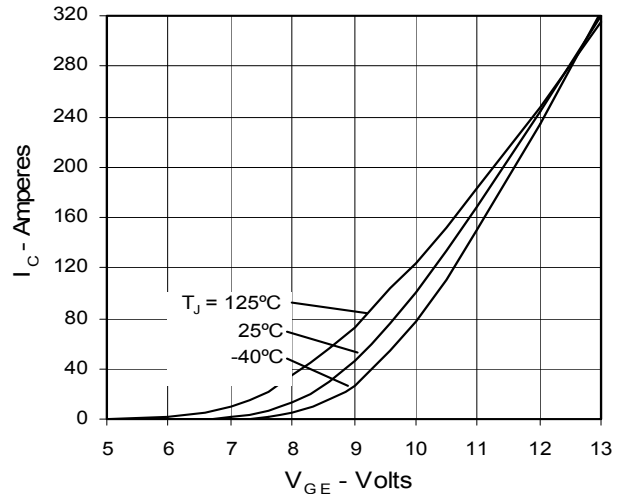


Fig. 7. Transconductance

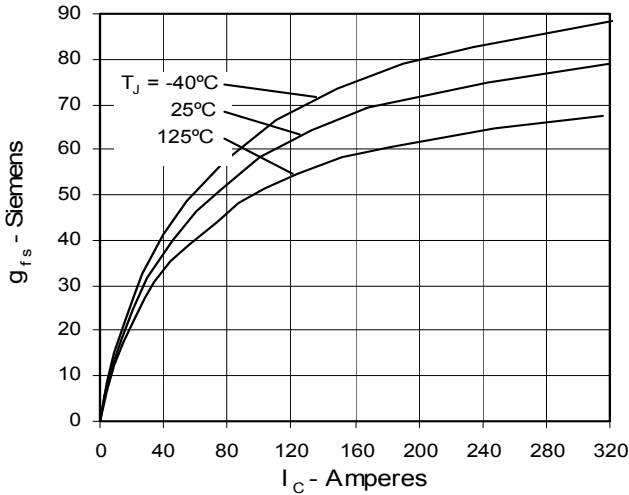


Fig. 8. Dependence of Turn-off Energy Loss on R_G

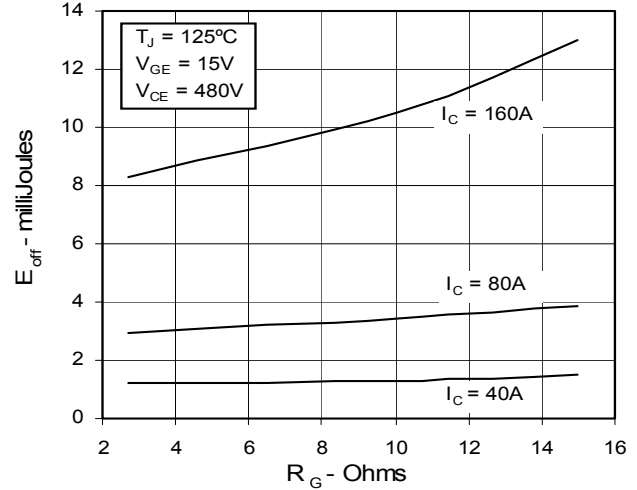


Fig. 9. Dependence of Turn-Off Energy Loss on I_C

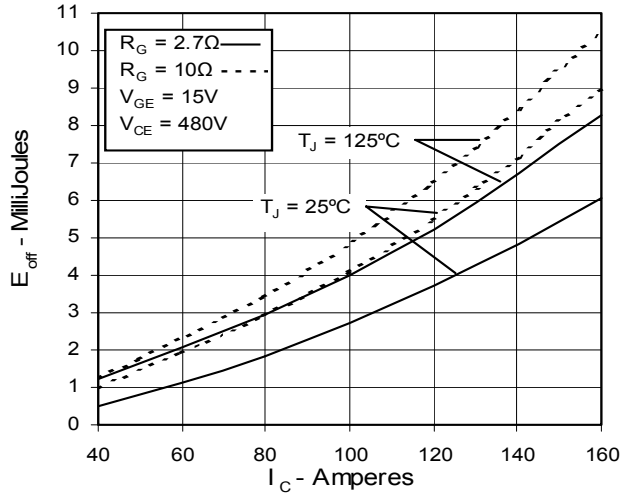


Fig. 10. Dependence of Turn-off Energy Loss on Temperature

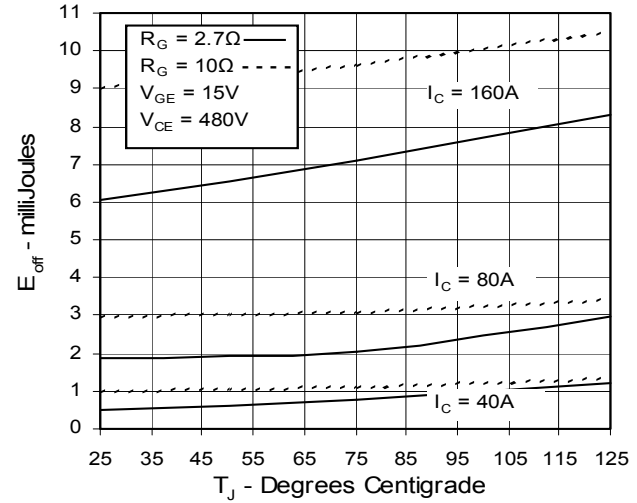


Fig. 11. Dependence of Turn-off Switching Time on R_G

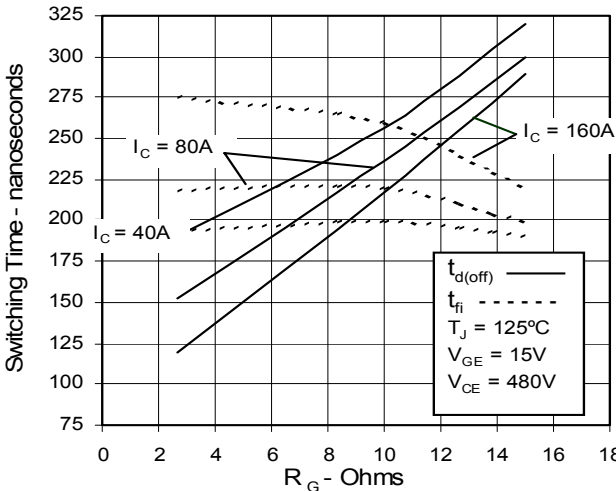
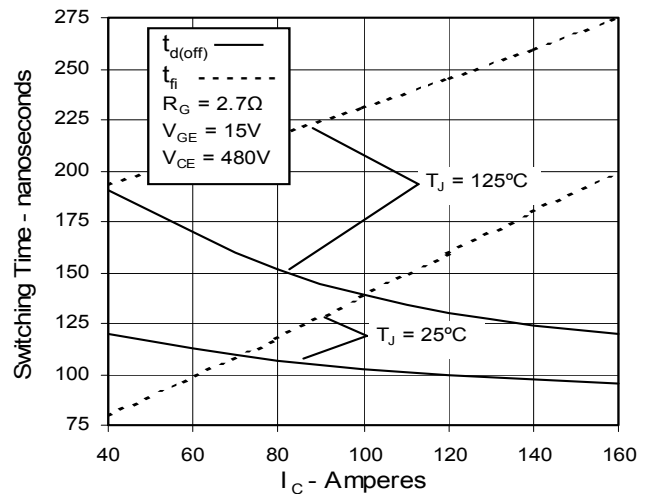


Fig. 12. Dependence of Turn-off Switching Time on I_C



IXYS reserves the right to change limits, test conditions, and dimensions.

IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents:

| | | | | | | | | | |
|-----------|-----------|-----------|-----------|-----------|-----------|-------------|-------------|-------------|-----------|
| 4,850,072 | 4,931,844 | 5,034,796 | 5,063,307 | 5,237,481 | 5,381,025 | 6,404,065B1 | 6,162,665 | 6,534,343 | 6,583,505 |
| 4,835,592 | 4,881,106 | 5,017,508 | 5,049,961 | 5,187,117 | 5,486,715 | 6,306,728B1 | 6,259,123B1 | 6,306,728B1 | 6,683,344 |

Fig. 13. Dependence of Turn-off Switching Time on Temperature

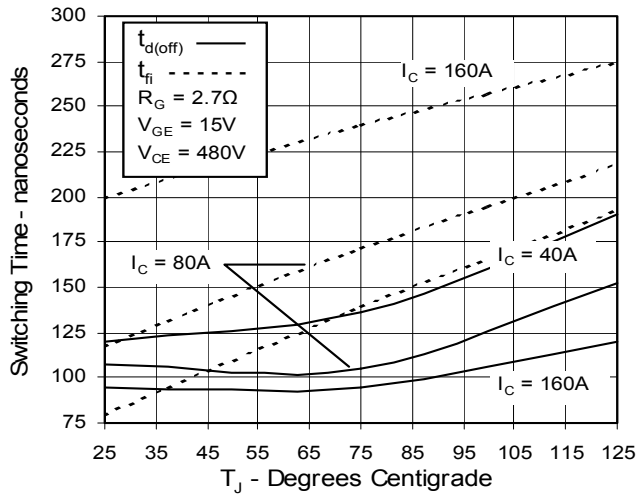


Fig. 14. Gate Charge

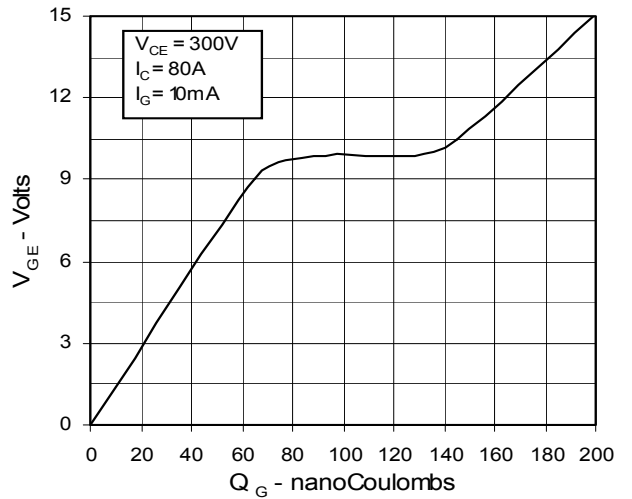


Fig. 15. Capacitance

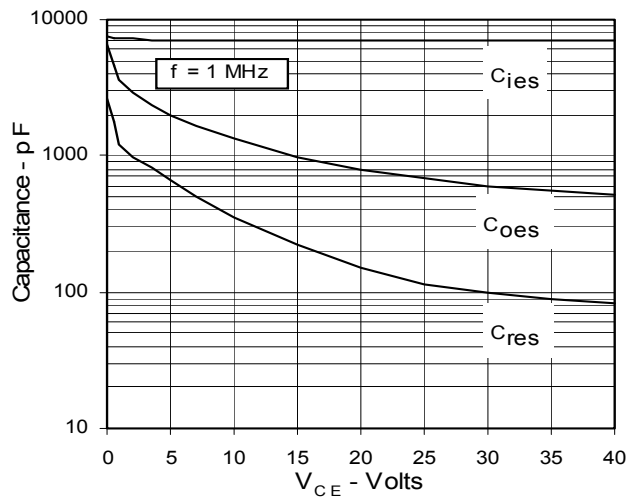
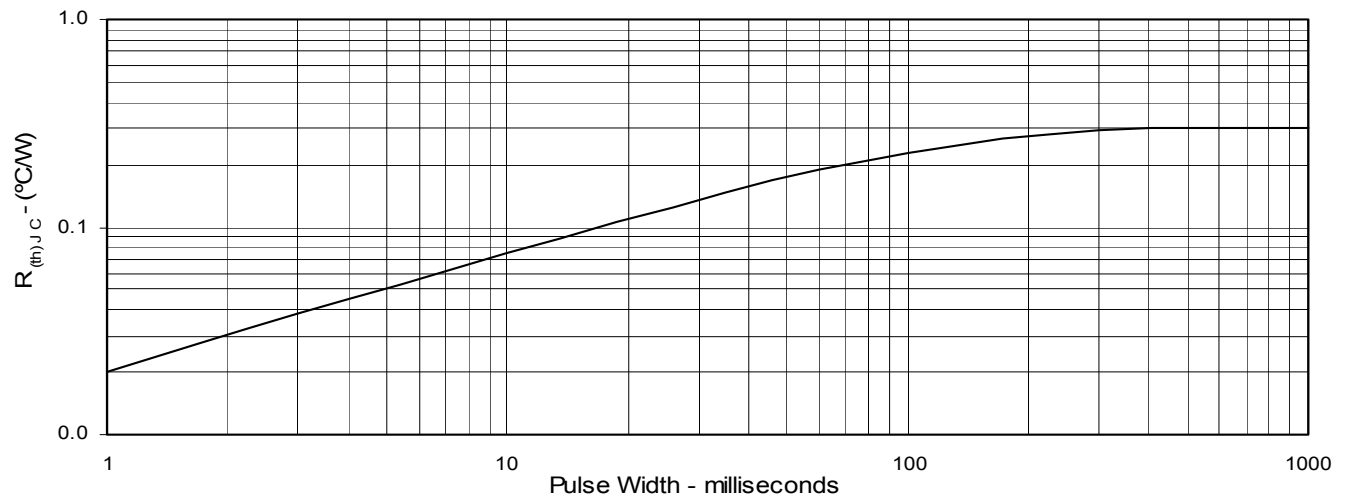


Fig. 16. Maximum Transient Thermal Resistance



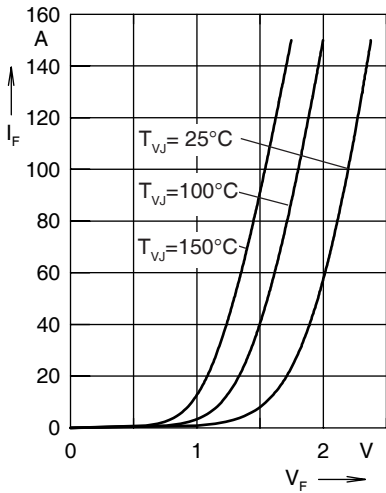


Fig. 17. Forward current I_F versus V_F

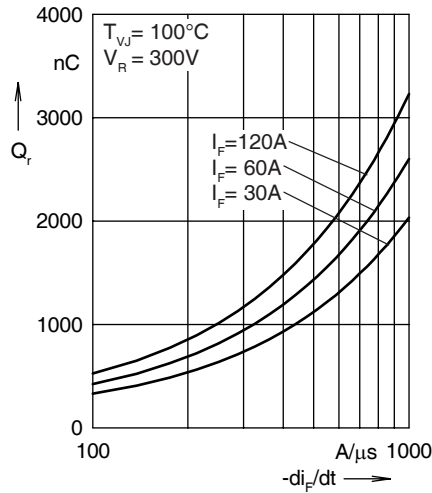


Fig. 18. Reverse recovery charge Q_r versus $-di_F/dt$

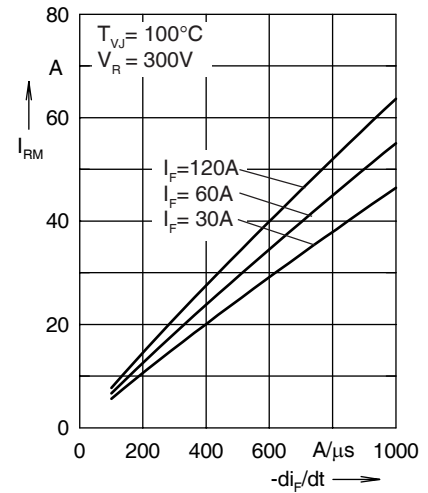


Fig. 19. Peak reverse current I_{RM} versus $-di_F/dt$

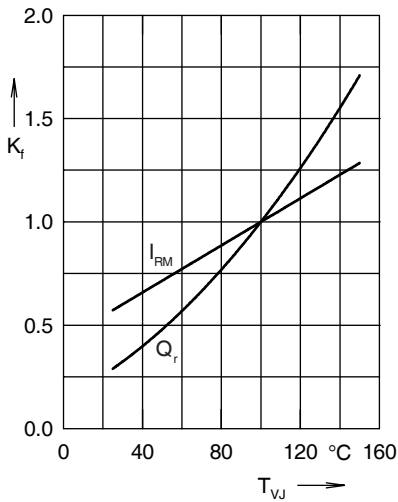


Fig. 20. Dynamic parameters Q_r , I_{RM} versus T_{VJ}

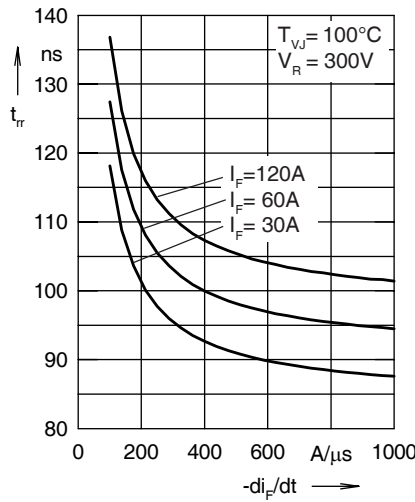


Fig. 21. Recovery time t_{tr} versus $-di_F/dt$

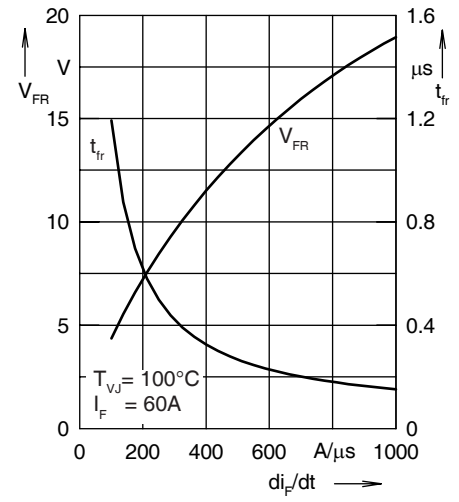


Fig. 22. Peak forward voltage V_{FR} and t_{tr} versus di_F/dt

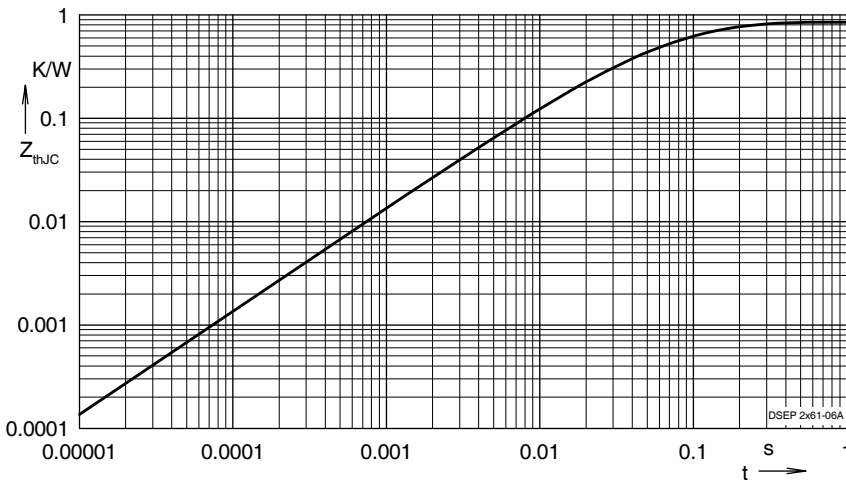


Fig. 7 Transient thermal resistance junction to case

Constants for Z_{thJC} calculation:

| i | R_{thi} (K/W) | t_i (s) |
|---|-----------------|-----------|
| 1 | 0.3073 | 0.0055 |
| 2 | 0.3533 | 0.0092 |
| 3 | 0.0887 | 0.0007 |
| 4 | 0.1008 | 0.0399 |

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